


<b>Search Notes</b>  	<b>Application/Control No.</b>  10598529	<b>Applicant(s)/Patent Under Reexamination</b>  HAMANAKA, MASAHIKO
	<b>Examiner</b>  STEPHEN R KOZIOL	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner
382	106, 118	8/10/2010	srk

SEARCH NOTES		
Search Notes	Date	Examiner
PALM inventor name double patenting search	8/10/2010	srk
EAST text search of above-cited classes for object pose estimation using weighted sharpness differences	8/10/2010	srk
NPL IEEE search for object pose estimation using weighted sharpness differences	8/10/2010	srk
JPO patent and utility model gazette db abstract search for object pose estimation using weighted sharpness differences	8/10/2010	srk

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/STEPHEN R KOZIOL/ Examiner.Art Unit 2624	
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